Sheet 1 of 2

FORM PTO-1449

INFORMATION DISCLOSURE STATEMENT BY APPLICANT(S) Atty Docket No.: Serial No.:

29287/141

To be assigned 10/765923

Inventors: Filed:

Hiroyuki MIZUNO et al. January 29, 2004

Group Art Unit:

2816 (anticipated

J.S. Zweizig (anticipated) Examiner:

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Examiner <u>Initial</u>	Patent <u>Number</u>	Patent <u>Date</u>	Name	Class/ Filing Subclass Date
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EXAMINER

DATE CONSIDERED

Jeffrey Zweizig

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Sheet 2 of 2

FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT BY APPLICANT(S)

Atty Docket No.: Serial No.:

29287/141

To be assigned 16/765923

Inventors:

Hiroyuki MIZUNO et al.

Filed:

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Group Art Unit: Examiner:

J.S. Zweizig (anticipated)

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